



Sheet 1 of 1

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 392.1802	APPLICATION NO. 10/603,747
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		FIRST NAMED INVENTOR Kazunori BAN, et al.		
		FILING DATE June 26, 2003	GROUP ART UNIT 3652-3661	

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
m-m	AA	4,876,728	10/1989	Roth	—	—	—
	AB						
	AC						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO
m-m	AD	8-271223	10/1996	Japan			X
	AE	9-53915	02/1997	Japan			X
	AF	9-91441	04/1997	Japan			X
	AG	1 043 689 A2	10/2000	European Patent Office			
↓	AH	1 043 689 A3	10/2000	European Patent Office			
	AI						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

TRANSLATION YES NO

m-m	AJ	Nakamura, Yuichi, et al., "Recognition of Overlapping 2-D Objects by Local Feature Construction Method", PROCEEDINGS OF THE INTERNATIONAL CONFERENCE ON PATTERN RECOGNITION, IEEE Com. Soc. Press, vol. 2, conf. 9, November 14, 1988.	✓	
m-m	AK	Magee, Michael, et al., "An Industrial Model Based Computer Vision System", JOURNAL OF MANUFACTURING SYSTEMS, Society of Manufacturing Engineers, Dearborn, MI, vol. 14, no. 3, 1995, pages 169-186.	✓	

EXAMINER <i>mcdowell mrs</i>	DATE CONSIDERED <i>9-8-07</i>
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

ATTORNEY DOCKET NO.
392.1802APPLICATION NO.
Not Yet AssignedFIRST NAMED INVENTOR
Kazunori BAN et al.FILING DATE
Concurrently Herewith

GROUP ART UNIT

Unknown 3661

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO
m m	AG	9-53915	02/25/97	JAPAN			Abstract
	AH	8-271223	10/18/96	JAPAN			Abstract
	AI	9-91441	04/04/97	JAPAN			Abstract
	AJ						
	AK						
	AL						

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

	AM	
	AN	
	AO	

EXAMINER	<i>mcdieune l m</i>	DATE CONSIDERED	<i>9-7-04</i>
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			